Search Notes		
		

Application/Control No.	Applicant(s)/Patent und Reexamination	ier
10/074,549	SINAIKO ET AL.	
Examiner	Art Unit	
Thao T. Tran	1711	

SEARCHED			
Class	Subclass	Date	Examiner
96	15,16	12/2/2005	тт
	95-98		
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D23	333		
	351		
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422	186		
	186.04		
	186.07		
	186.14		
	186.15		

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
EAST; inventor name search	12/2/2005	ŦΤ	